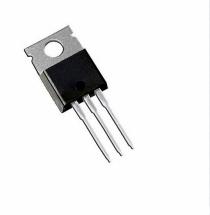


AUIRF1404Z Datasheet

www.digi-electronics.com



https://www.DiGi-Electronics.com

DiGi Electronics Part Number

AUIRF1404Z-DG

Manufacturer

Infineon Technologies

Manufacturer Product Number

AUIRF1404Z

Description

MOSFET N-CH 40V 160A TO220AB

Detailed Description

N-Channel 40 V 160A (Tc) 200W (Tc) Through Hole

TO-220AB



Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com

DiGi is a global authorized distributor of electronic components.



Purchase and inquiry

Manufacturer Product Number:	Manufacturer:
AUIRF1404Z	Infineon Technologies
Series:	Product Status:
HEXFET®	Last Time Buy
FET Type:	Technology:
N-Channel	MOSFET (Metal Oxide)
Drain to Source Voltage (Vdss):	Current - Continuous Drain (Id) @ 25°C:
40 V	160A (Tc)
Drive Voltage (Max Rds On, Min Rds On):	Rds On (Max) @ Id, Vgs:
10V	3.7mOhm @ 75A, 10V
Vgs(th) (Max) @ ld:	Gate Charge (Qg) (Max) @ Vgs:
4V @ 250μA	150 nC @ 10 V
Vgs (Max):	Input Capacitance (Ciss) (Max) @ Vds:
±20V	4340 pF @ 25 V
FET Feature:	Power Dissipation (Max):
	200W (Tc)
Operating Temperature:	Mounting Type:
-55°C ~ 175°C (TJ)	Through Hole
Supplier Device Package:	Package / Case:
TO-220AB	TO-220-3
Base Product Number:	
AUIRF1404	

Environmental & Export classification

8541.29.0095

RoHS Status:	Moisture Sensitivity Level (MSL):
ROHS3 Compliant	1 (Unlimited)
REACH Status:	ECCN:
REACH Unaffected	EAR99
HTSUS:	



AUTOMOTIVE GRADE

AUIRF1404Z AUIRF1404ZS AUIRF1404ZL

HEXFET® Power MOSFET

Features

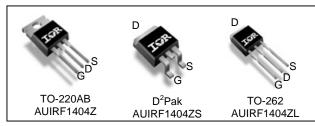
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

G S

V _{DSS}	40V
R _{DS(on)} max.	3.7m $Ω$
D (Silicon Limited)	180A ●
D (Package Limited)	160A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base next number	Deelsege Type	Standard Pack		Ordershie Port Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRF1404Z	TO-220	Tube	50	AUIRF1404Z
AUIRF1404ZL	TO-262	Tube	50	AUIRF1404ZL
ALUDE440470	D ² Dole	Tube	50	AUIRF1404ZS
AUIRF1404ZS	D ² -Pak Ta	Tape and Reel Left	800	AUIRF1404ZSTRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	180❶	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	120] ,
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	160	A
I _{DM}	Pulsed Drain Current ①	710	=
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	330	m l
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	480	- mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy ©		mJ
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	1
	Mounting torque, 6-32 or M3 screw ⑦	10 lbf•in (1.1N•m)	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.759	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface ⑦	0.50		900
$R_{ hetaJA}$	Junction-to-Ambient ⑦		62	°C/W
$R_{ hetaJA}$	Junction-to-Ambient (PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.033		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		2.7	3.7	mΩ	$V_{GS} = 10V, I_D = 75A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
gfs	Forward Trans conductance	170			S	$V_{DS} = 25V, I_{D} = 75A$
ı	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
1	Gate-to-Source Forward Leakage			200	n ^	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

otal Gate Charge		100	150		$I_D = 75A$
ate-to-Source Charge		31		nC	$V_{DS} = 32V$
ate-to-Drain Charge		42			V _{GS} = 10V3
urn-On Delay Time		18			$V_{DD} = 20V$
ise Time		110		no	$I_D = 75A$
urn-Off Delay Time		36		115	$R_G = 3.0\Omega$
all Time		58			V _{GS} = 10V ③
ternal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
ternal Source Inductance		7.5			from package and center of die contact
put Capacitance		4340			$V_{GS} = 0V$
utput Capacitance		1030			$V_{DS} = 25V$
everse Transfer Capacitance		550		ъ.Г	f = 1.0MHz
utput Capacitance		3300		þΓ	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
utput Capacitance		920			$V_{GS} = 0V$, $V_{DS} = 32V$ $f = 1.0MHz$
ffective Output Capacitance		1350			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V $
	ate-to-Source Charge ate-to-Drain Charge urn-On Delay Time ise Time urn-Off Delay Time all Time ternal Drain Inductance ternal Source Inductance put Capacitance utput Capacitance everse Transfer Capacitance utput Capacitance utput Capacitance utput Capacitance	ate-to-Source Charge —— ate-to-Drain Charge —— urn-On Delay Time —— ise Time —— urn-Off Delay Time —— all Time —— ternal Drain Inductance —— ternal Source Inductance —— utput Capacitance ——	ate-to-Source Charge — 31 ate-to-Drain Charge — 42 urn-On Delay Time — 18 ise Time — 110 urn-Off Delay Time — 36 all Time — 58 ternal Drain Inductance — 4.5 ternal Source Inductance — 7.5 put Capacitance — 4340 utput Capacitance — 550 utput Capacitance — 3300 utput Capacitance — 920	ate-to-Source Charge — 31 — ate-to-Drain Charge — 42 — urn-On Delay Time — 18 — ise Time — 110 — urn-Off Delay Time — 36 — all Time — 58 — ternal Drain Inductance — 4.5 — ternal Source Inductance — 7.5 — put Capacitance — 4340 — utput Capacitance — 550 — utput Capacitance — 3300 — utput Capacitance — 920 —	ate-to-Source Charge — 31 — nC ate-to-Drain Charge — 42 — urn-On Delay Time — 18 — ise Time — 110 — urn-Off Delay Time — 36 — all Time — 58 — ternal Drain Inductance — 4.5 — ternal Source Inductance — 7.5 — put Capacitance — 4340 — utput Capacitance — 550 — utput Capacitance — 3300 — utput Capacitance — 920 —

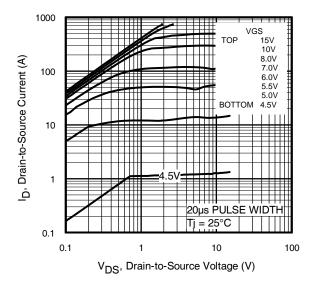
Diode Characteristics

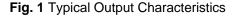
	Parameter	Min.	Тур.	Max.	Units	Conditions	
I _S	Continuous Source Current (Body Diode)			160		MOSFET symbol showing the	
I _{SM}	Pulsed Source Current (Body Diode) ①			750		integral reverse p-n junction diode.	
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V$ ③	
t _{rr}	Reverse Recovery Time		28	42	ns	$T_J = 25^{\circ}C$, $I_F = 75A$, $V_{DD} = 20V$	
Q_{rr}	Reverse Recovery Charge		34	51	nC	di/dt = 100A/µs ③	
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by T_{Jmax} , starting $T_J = 25^{\circ}C$, L = 0.11mH, $R_G = 25\Omega$, $I_{AS} = 75$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- © This value determined from sample failure population, starting $T_J = 25$ °C, L = 0.11mH, $R_G = 25\Omega$, $I_{AS} = 75$ A, $V_{GS} = 10$ V.
- This is only applied to TO-220AB pakcage.
- This is applied to D²Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- 9 TO-220 device will have an Rth value of 0.65°C/W.
- Calculated continuous current based on maximum allowable junction temperature. Package limitation current limit is 160A.
 Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
 (Refer to AN-1140)







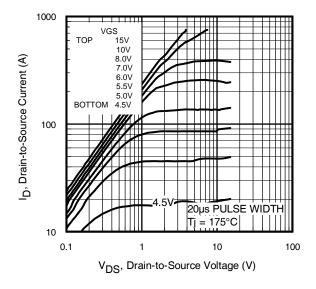


Fig. 2 Typical Output Characteristics

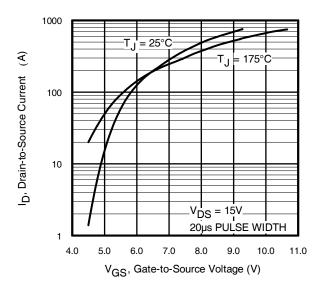


Fig. 3 Typical Transfer Characteristics

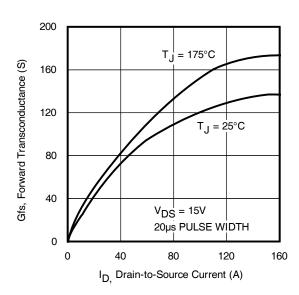


Fig. 4 Typical Forward Trans conductance vs. Drain Current



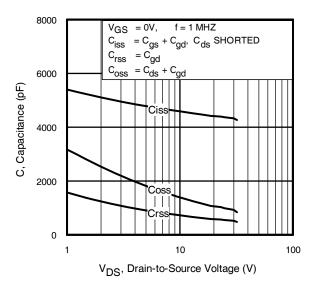


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

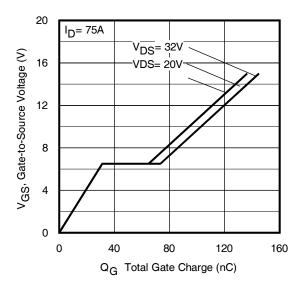


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

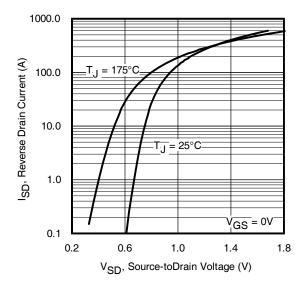


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

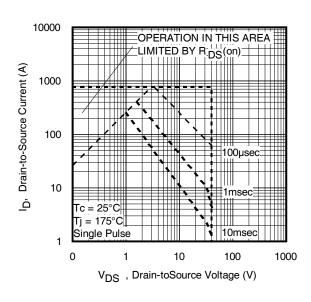
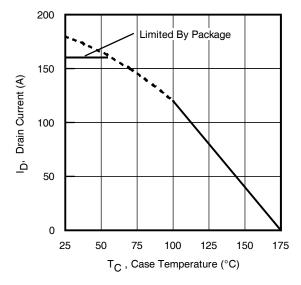


Fig 8. Maximum Safe Operating Area





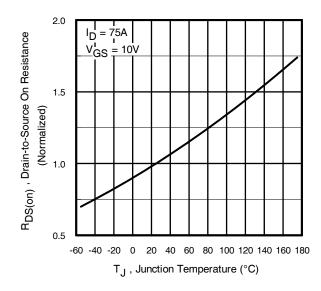


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

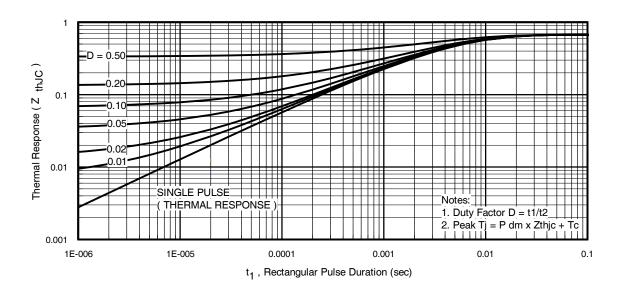


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



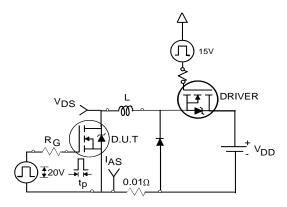


Fig 12a. Unclamped Inductive Test Circuit

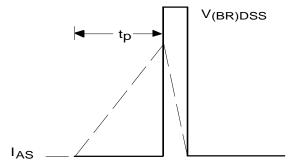


Fig 12b. Unclamped Inductive Waveforms

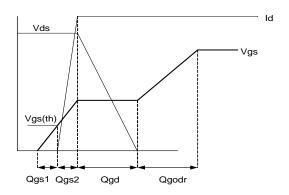


Fig 13a. Gate Charge Waveform

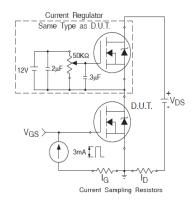


Fig 13b. Gate Charge Test Circuit

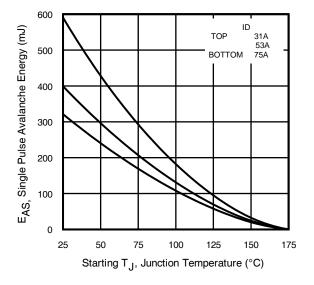


Fig 12c. Maximum Avalanche Energy vs. Drain Current

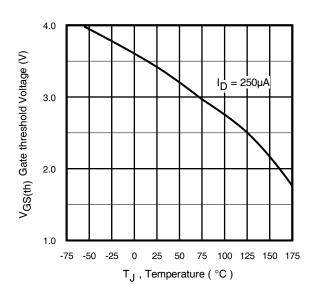


Fig 14. Threshold Voltage vs. Temperature

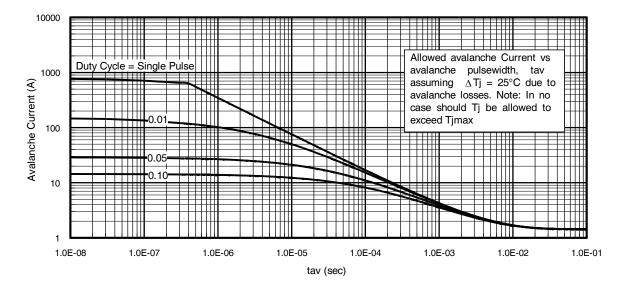


Fig 15. Typical Avalanche Current vs. Pulse width

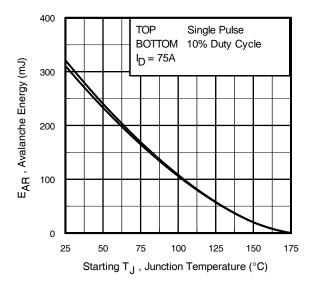


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV-I}_{av} \text{)} = \Delta \text{T/ } Z_{thJC} \\ I_{av} &= 2\Delta \text{T/ [} 1.3 \cdot \text{BV-Z}_{th} \text{]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

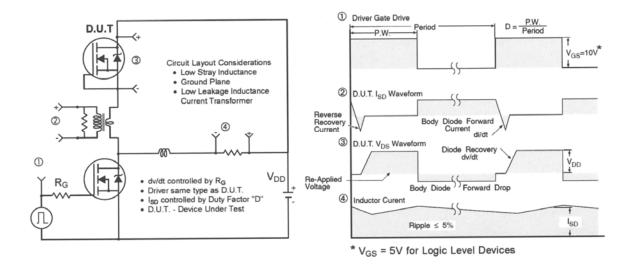


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

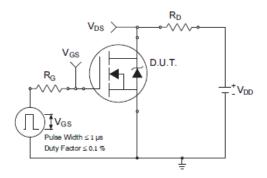


Fig 18a. Switching Time Test Circuit

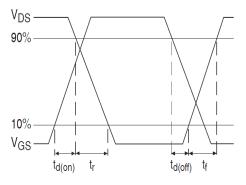
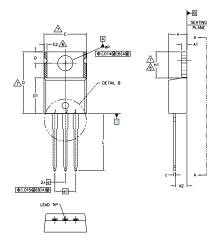
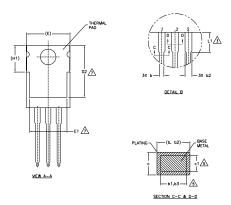


Fig 18b. Switching Time Waveforms



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONING AND TOLERANGING AS PER ASMETTA, SWITTA, S MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES				
	MIN.	MAX.	MIN.	MAX.	NOTES			
Α	3.56	4.83	.140	.190				
A1	1.14	1.40	.045	.055				
A2	2.03	2.92	.080	.115				
b	0.38	1.01	.015	.040				
b1	0.38	0.97	.015	.038	5			
b2	1.14	1.78	.045	.070				
b3	1,14	1.73	.045	.068	5			
С	0.36	0.61	.014	.024				
c1	0.36	0.56	.014	.022	5			
D	14.22	16.51	.560	.650	4			
D1	8.38	9.02	.330	.355				
D2	11.68	12.88	.460	.507	7			
E	9.65	10.67	.380	.420	4,7			
E1	6.86	8.89	.270	.350	7			
E2	-	0.76	-	.030	8			
e	2.54 5.08	BSC	.100 BSC .200 BSC					
e1	5.08	BSC	.200 BSC					
H1	5.84	6.86	.230	.270	7,8			
L	12.70	14.73	.500	.580				
L1	3.56	4.06	.140	.160	3			
ØΡ	3.54	4.08	.139	.161				
Q	2.54	3.42	.100	.135				

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

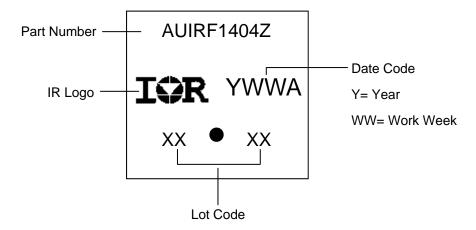
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

- 1.- ANODE 2.- CATHODE 3.- ANODE

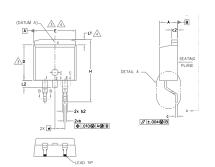
TO-220AB Part Marking Information

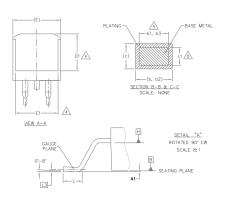


TO-220AB package is not recommended for Surface Mount Application.



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL
NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED
AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		DIMEN	SIONS		N
M B	MILLIM	ETERS	INC	HES	O T E S
0 L	MIN.	MAX.	MIN.	MAX.	E S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
Ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	.100 BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

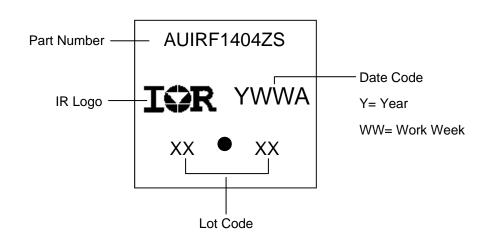
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

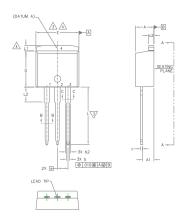
2, 4.- COLLECTOR 3.- EMITTER

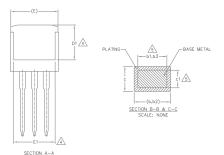
D²Pak (TO-263AB) Part Marking Information





TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

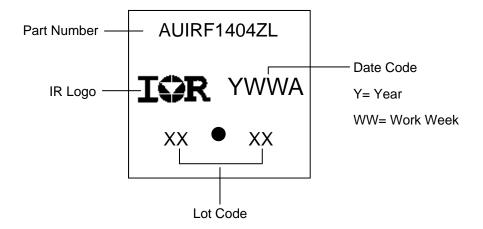
HEXFET DIODES

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

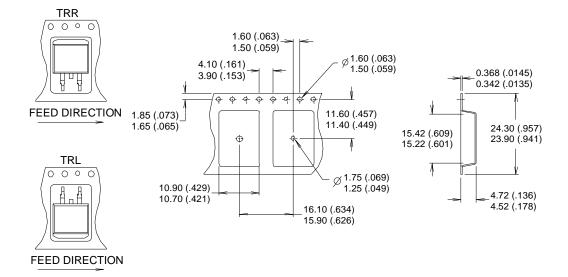
S Y M	DIMENSIONS				N
В	MILLIMETERS		INCHES		O T E S
O L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
ь3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54 BSC		.100 BSC		
L	13.46	14.10	.530	.555	
L1	_	1.65	-	.065	4
L2	3.56	3.71	.140	.146	

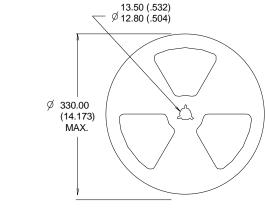
TO-262 Part Marking Information





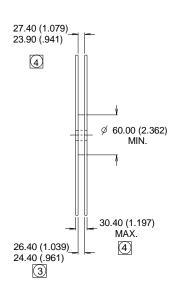
D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- (4) INCLUDES FLANGE DISTORTION @ OUTER EDGE.





Qualification Information

Qualification Level		Automotive (per AEC-Q101)		
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.		
Moisture Sensitivity Level		TO-220AB	N/A	
		TO-262 D ² -Pak	MSL1	
ESD	Machine Model	Class M4 [†] AEC-Q101-002		
	Human Body Model	Class H1C [†] AEC-Q101-001		
	Charged Device Model	Class C3 [†] AEC-Q101-005		
RoHS Compliant		Yes		

[†] Highest passing voltage.

Revision History

Date	Comments		
11/11/2015	Updated datasheet with corporate template		
11/11/2015	Corrected ordering table on page 1.		

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.



OUR CERTIFICATE

DiGi provide top-quality products and perfect service for customer worldwide through standardization, technological innovation and continuous improvement. DiGi through third-party certification, we striciy control the quality of products and services. Welcome your RFQ to Email: Info@DiGi-Electronics.com

















Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com